

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|-------|--|---|------------------|---------|------------------|
| L1 | 7198 | (250/306,307,310,311,492.3,492.2,492.22).ccls. | US-PGPUB; USPAT | OR | ON | 2006/01/06 11:57 |
| L2 | 6764 | (324/750,751,754,158.1,537).ccls. | US-PGPUB; USPAT | OR | ON | 2006/01/06 11:58 |
| L3 | 1086 | (356/334,394).ccls. | US-PGPUB; USPAT | OR | ON | 2006/01/06 11:58 |
| L4 | 598 | (156/89.12,379).ccls. | US-PGPUB; USPAT | OR | ON | 2006/01/06 11:58 |
| L5 | 15446 | L1 or L2 or L3 or L4 | US-PGPUB; USPAT | OR | ON | 2006/01/06 11:58 |
| L6 | 171 | L5 and ((silicon adj on adj insulator) or SOI) | US-PGPUB; USPAT | OR | OFF | 2006/01/06 12:00 |
| L7 | 0 | L6 and (semiconductor near2 die) and (inspection with (electron or SEM)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/01/06 12:00 |
| L8 | 40 | L5 and (semiconductor near2 die) and (inspection with (electron or SEM)) | US-PGPUB; USPAT | OR | ON | 2006/01/06 11:59 |
| L9 | 0 | L8 and ((silicon adj on adj insulator) or SOI) | US-PGPUB; USPAT | OR | OFF | 2006/01/06 11:59 |
| L10 | 100 | (semiconductor near2 die) and (inspection with (electron or SEM)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/01/06 12:00 |
| L11 | 0 | L10 and ((silicon adj on adj insulator) or SOI) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2006/01/06 12:00 |